

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/044,195	SYED, MAJID	
Examiner	Art Unit	
Thuong (Tina) T. Nguyen	2155	

SEARCHED						
Class	Subclass	Date	Examiner			
709	225,235, 231	5/21/2008	TH			
725	85	5/21/2008	TH			

INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST	5/21/2008	ТН	
IEEE	5/21/2008	ТН	